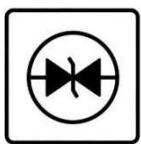




ESD



TVS



TSS



MOV



GDT



PLED

SI2303CDS-T1-GE3-MS

Product specification

Description

These P-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

BVDSS	RDS(ON)	ID
-30V	150mΩ	-3.0A

Features

- -30V, -3.0A, RDS(ON) = 150mΩ @ VGS = -10V
- Fast switching
- Green Device Available
- Suit for -4.5V Gate Drive Applications

Applications

- Notebook
- Load Switch
- Battery Protection
- Hand-held Instruments

Reference News

PACKAGE OUTLINE	P-Channel MOSFET	Marking
 SOT-23		

Absolute Maximum Ratings (TA=25°C unless otherwise noted)

Symbol	Parameter	Rating	Units
V _{DS}	Drain-Source Voltage	-30	V
V _{GS}	Gate-Source Voltage	±20	V
I _D	Drain Current – Continuous (TA=25°C)	-3.0	A
	Drain Current – Continuous (TA=70°C)	-2.0	A
I _{DM}	Drain Current – Pulsed ¹	-12	A
P _D	Power Dissipation (TA=25°C)	1.56	W
	Power Dissipation – Derate above 25°C	0.012	W/°C
T _{STG}	Storage Temperature Range	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	°C

Thermal Characteristics

Symbol	Parameter	Typ.	Max.	Unit
$R_{\theta JA}$	Thermal Resistance Junction to ambient	---	80	°C/W

Electrical Characteristics (T_J=25 °C, unless otherwise noted)
Off Characteristics

Parameter	Conditions	Min.	Typ.	Max.	Unit
Drain-Source Breakdown Voltage	$V_{GS}=0V, I_D=-250\mu A$	-30	---	---	V
BV_{DSS} Temperature Coefficient	Reference to 25°C, $I_D=-1mA$	---	-0.02	---	°C/V
Drain-Source Leakage Current	$V_{DS}=-27V, V_{GS}=0V, T_J=25°C$	---	---	-1	uA
	$V_{DS}=-24V, V_{GS}=0V, T_J=125°C$	---	---	-10	uA
Gate-Source Leakage Current	$V_{GS}=\pm 20V, V_{DS}=0V$	---	---	±100	nA

On Characteristics

$R_{DS(ON)}$	Static Drain-Source On-Resistance	$V_{GS}=-10V, I_D=-2A$	---	150	190	mΩ
		$V_{GS}=-4.5V, I_D=-1.5A$	---	190	300	mΩ
$V_{GS(th)}$	Gate Threshold Voltage	$V_{GS}=V_{DS}, I_D=-250\mu A$	-1.0	-1.5	-2.5	V
			---	-2.8	---	°C/mV
g_{fs}	Forward Transconductance	$V_{DS}=-10V, I_D=-1A$	---	3	---	S

Dynamic and switching Characteristics

Q_g	Total Gate Charge ^{2, 3}	$V_{DS}=-24V, V_{GS}=-4.5V, I_D=-2A$	---	2.5	---	nC
Q_{gs}	Gate-Source Charge ^{2, 3}		---	0.1	---	
Q_{gd}	Gate-Drain Charge ^{2, 3}		---	1.8	---	
$T_{d(on)}$	Turn-On Delay Time ^{2, 3}	$V_{DD}=-15V, V_{GS}=-10V, R_G=6\Omega I_D=-1A$	---	6.1	---	ns
T_r	Rise Time ^{2, 3}		---	8.7	---	
$T_{d(off)}$	Turn-Off Delay Time ^{2, 3}		---	33.2	---	
T_f	Fall Time ^{2, 3}		---	3.7	---	
C_{iss}	Input Capacitance		---	226	---	pF
C_{oss}	Output Capacitance	$V_{DS}=-15V, V_{GS}=0V, F=1MHz$	---	39	---	
C_{rss}	Reverse Transfer Capacitance		---	29	---	
R_g	Gate resistance	$V_{GS}=0V, V_{DS}=0V, F=1MHz$	---	9.5	---	Ω

Drain-Source Diode Characteristics and Maximum Ratings

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current	$V_G=V_D=0V, \text{Force Current}$	---	---	-3.0	A
I_{SM}	Pulsed Source Current		---	---	-6.0	A
V_{SD}	Diode Forward Voltage	$V_{GS}=0V, I_s=-1A, T_J=25°C$	---	---	-1.2	V

Note :

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed, pulse width $\leq 300\mu s$, duty cycle $\leq 2\%$.
3. Essentially independent of operating temperature.

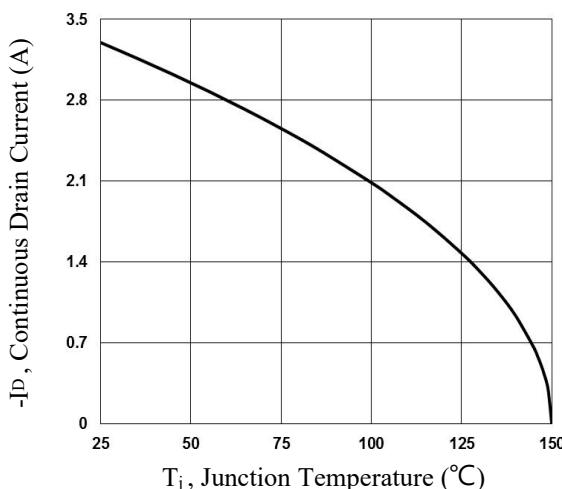


Fig.1 Continuous Drain Current vs. T_c

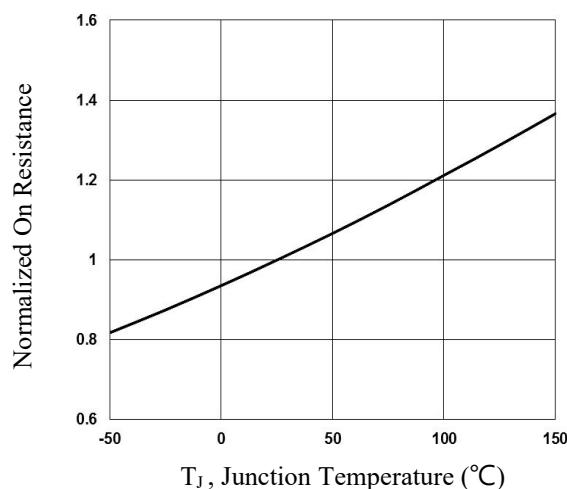


Fig.2 Normalized R_{DSON} vs. T_J

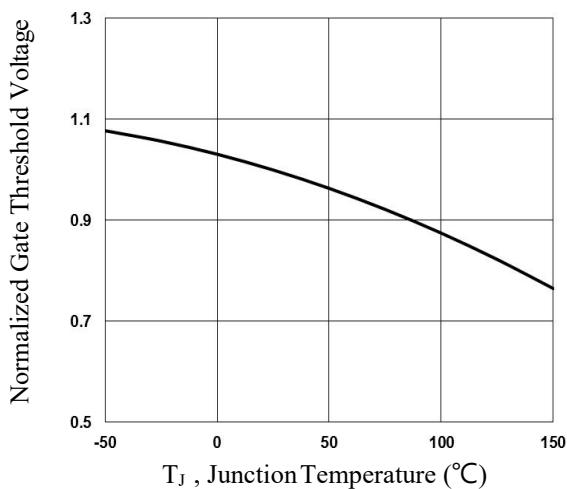


Fig.3 Normalized V_{th} vs. T_J

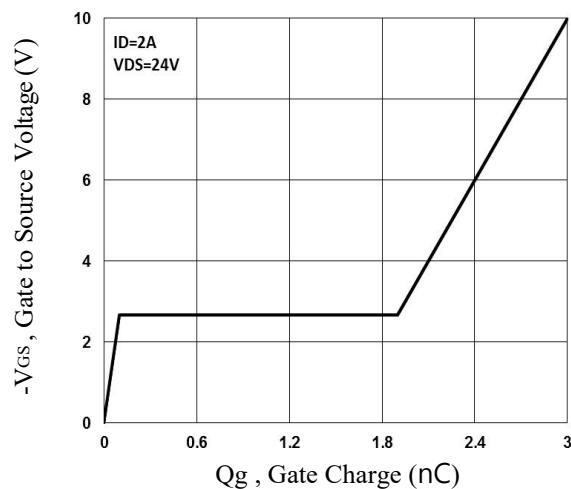


Fig.4 Gate Charge Waveform

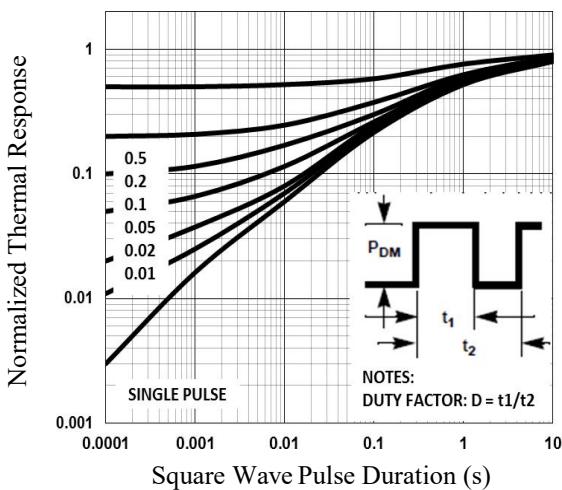


Fig.5 Normalized Transient Impedance

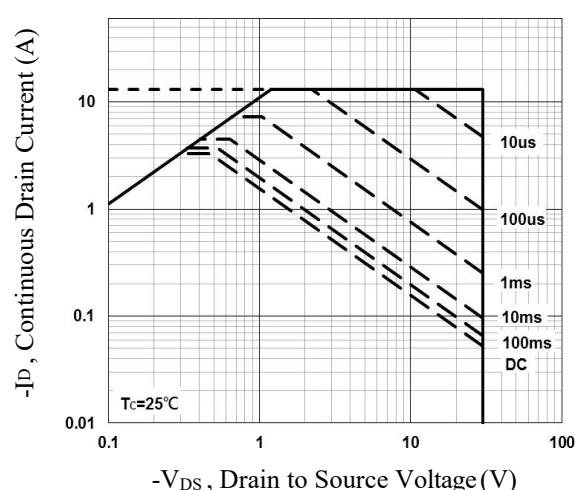


Fig.6 Maximum Safe Operation Area

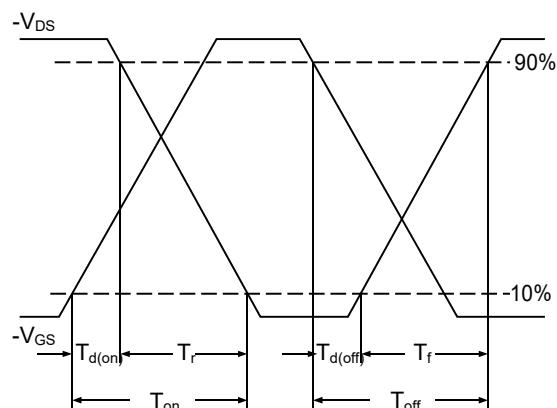


Fig.7 Switching Time Waveform

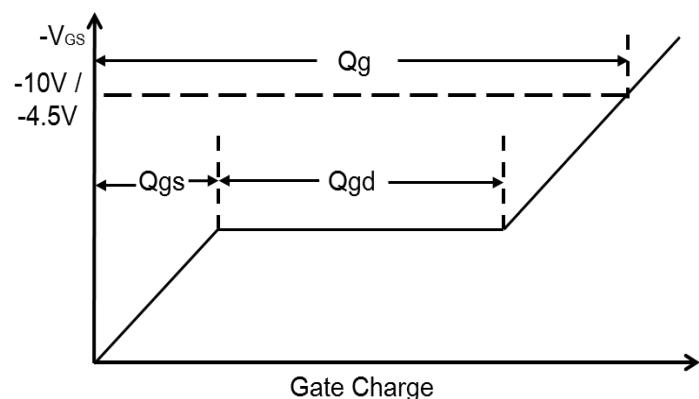
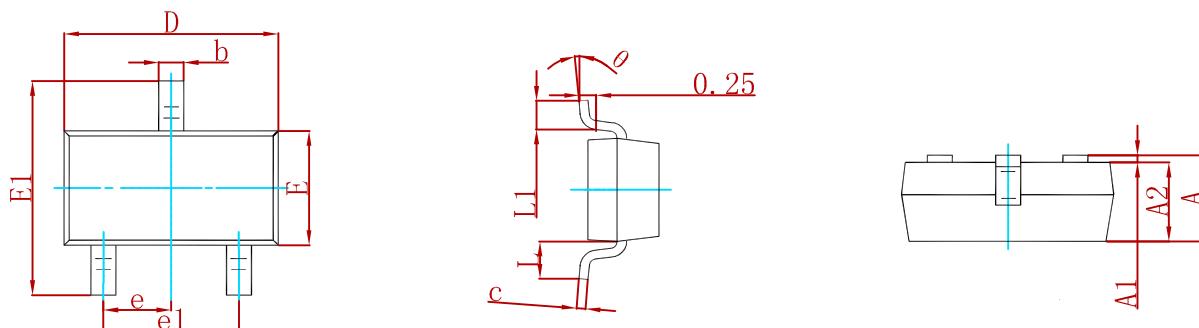


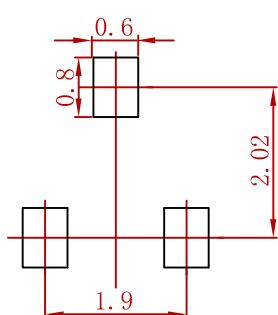
Fig.8 Gate Charge Waveform

PACKAGE MECHANICAL DATA



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min	Max	Min	Max
A	0.900	1.150	0.035	0.045
A1	0.000	0.100	0.000	0.004
A2	0.900	1.050	0.035	0.041
b	0.300	0.500	0.012	0.020
c	0.080	0.150	0.003	0.006
D	2.800	3.000	0.110	0.118
E	1.200	1.400	0.047	0.055
E1	2.250	2.550	0.089	0.100
e	0.950 TYP		0.037 TYP	
e1	1.800	2.000	0.071	0.079
L	0.550 REF		0.022 REF	
L1	0.300	0.500	0.012	0.020
θ	0°	8°	0°	8°

Suggested Pad Layout



Note:

1. Controlling dimension: in millimeters.
2. General tolerance: ± 0.05 mm.
3. The pad layout is for reference purposes only.

REEL SPECIFICATION

P/N	PKG	QTY
SI2303CDS-T1-GE3-MS	SOT-23	3000

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